Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/647,540	NAPHADE ET AL.
Examiner	Art Unit
ALEX LIEW	2624

	CEARCHER						
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Class	Subclass	Date	Examiner				
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

DATE  8/27/2008	EXMR AL
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